

<b>Notice of References Cited</b>	Application/Control No. 10/779,904	Applicant(s)/Patent Under Reexamination ISHIDA ET AL.	
	Examiner OSCAR A. LOUIE	Art Unit 2436	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,483,170	01-1996	Beasley et al.	324/537
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"IDD pulse response testing applied to complex CMOS ICs," Beasley et al., Test Conference, 1997. Proceedings., International, IEEE, 11/1-6/1997.
	V	"Defect detection with transient current testing and its potential for deep submicron CMOS ICs," Sachdev et al., Test Conference, 1998. Proceedings., International, 18-23 Oct 1998.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.